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FOREIGN PATENT DOCUMENTS

7/27 Streibl, M. et al. "SAW Tomography-Spatially Resolved Charge Detection by SAW in Semiconductor Structures for Imaging Applications", 1999 IEEE Ultrasonics Symposium Proceedings, International Symposium (Cat. No. 99CH37027), 1999 IEEE Ultrasonics Symposium, Proceedings, International Symposium, Caesars Tahoe, NV, U.S.A. 17-20 Oct. 1999, Pages 11-14, Vol. 1, XP002156577, 1999, Piscataway, NJ, U.S.A., IEEE, U.S.A., ISBN: 0-7803-5722-1

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